Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/032,729	CHEN ET AL.
Examiner	Art Unit
John L. Shew	2616

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	347,352	9/5/2006	JS
	363,367		
	368,371		
	378,379		
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	389,390		
	395.3		
	412		
	428,429	9/6/2006	JS
708	232,273	9/6/2006	JS
709	230,236	9/6/2006	JS
	238,243		
	250		
710	310	9/6/2006	JS

INT	ERFERENC	E SEARCH	ED
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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